

LDEPD1120KA5N00

Aliases (DEPD1120KA5N00)

LDE, Film, Metallized PEN Stacked, Automotive Grade, 1200 pF, 10%, 200 VAC, 630 VDC, 125°C, 2220, 2mm



Click [here](#) for the 3D model.

Dimensions

| | |
|-----------|-------------------|
| Chip Size | 2220 |
| L | 6mm +/-0.3mm |
| W | 5mm +/-0.4mm |
| T | 2mm MAX |
| B | 0.4mm +0.5/-0.3mm |

Packaging Specifications

| | |
|--------------------|------|
| Packaging | T&R |
| Packaging Quantity | 3000 |

General Information

| | |
|----------------|------------------------|
| Series | LDE |
| Dielectric | Metallized PEN Stacked |
| Style | SMD Chip |
| Features | Automotive Grade |
| RoHS | Yes |
| Qualifications | AEC-Q200 |
| AEC-Q200 | Yes |
| Shelf Life | 104 Weeks |
| MSL | 2a |

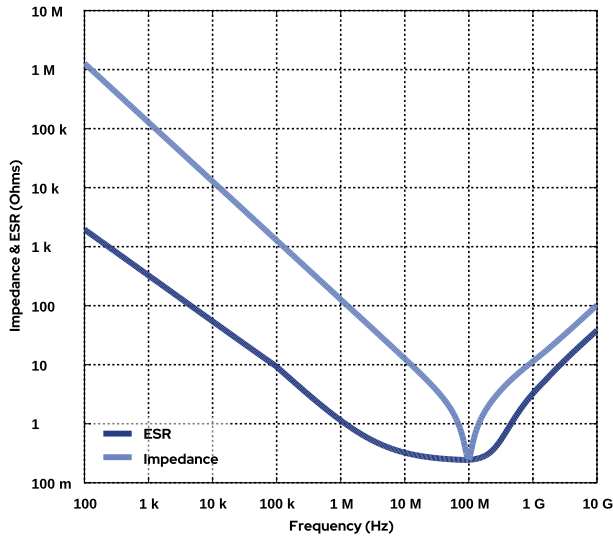
Specifications

| | |
|-----------------------|------------|
| Capacitance | 1200 pF |
| Capacitance Tolerance | 10% |
| Voltage AC | 200 VAC |
| Voltage DC | 630 VDC |
| Temperature Range | -55/+125°C |
| Rated Temperature | 125°C |
| Dissipation Factor | 0.8% 1kHz |
| Insulation Resistance | 1 GOhms |
| Max dV/dt | 100 V/us |

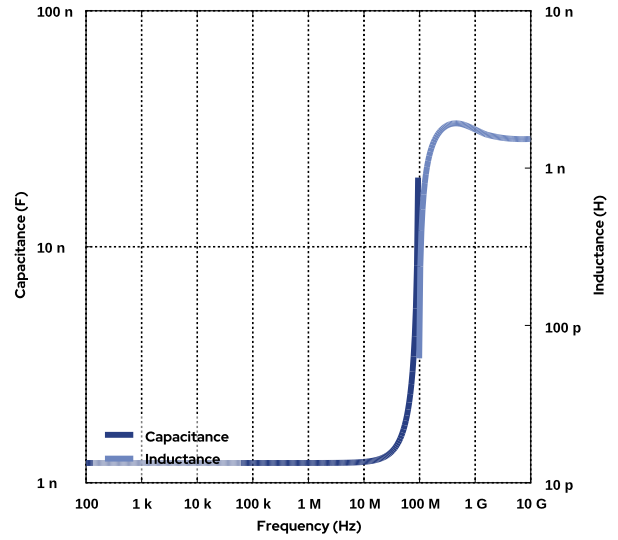
Simulations

For the complete simulation environment please visit [K-SIM](#).

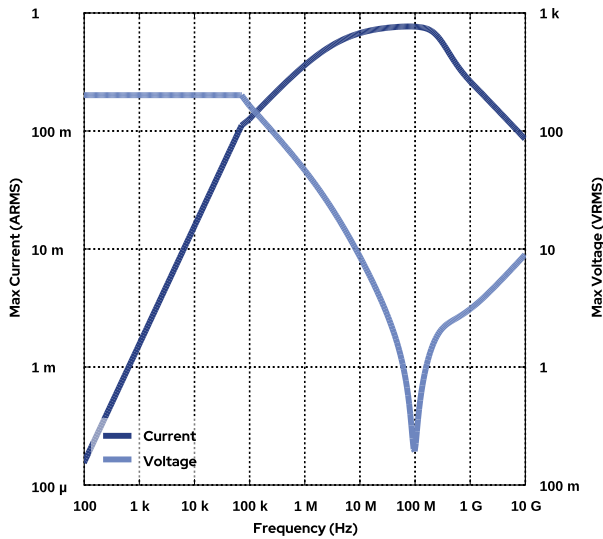
Impedance and ESR



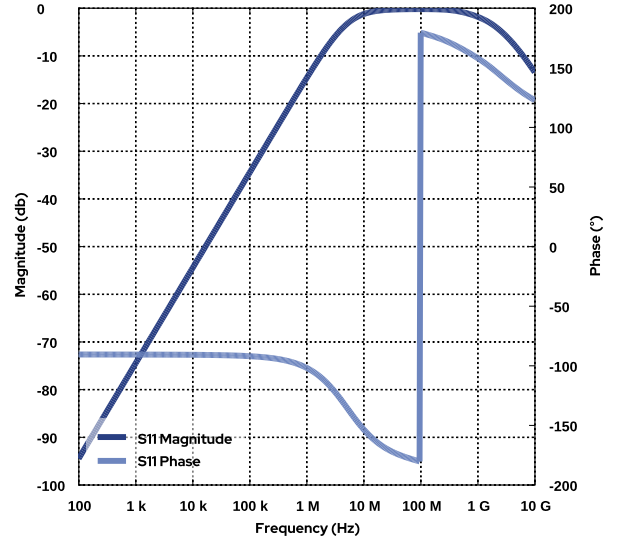
Capacitance and Inductance

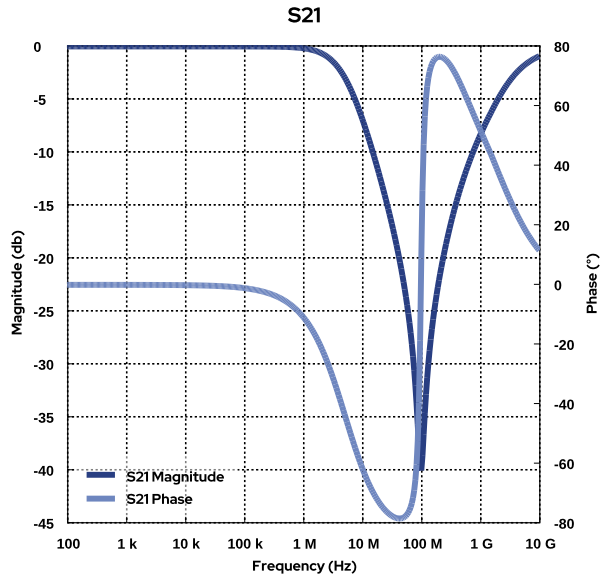


Current and Voltage



S11





These are simulations.

This is not a specification!

The responses shown represent the typical response for each part type. Specific responses may vary, depending on manufacturing variation affects of all parameters involved, including the specified tolerances applied to capacitance and unspecified variations of ESR, ESL, and leakage resistance.

The responses shown do not represent a specified or implied maximum capability of the device for all applications.

- The ESR used for ripple "Ripple Current/Voltage vs. Frequency" plots is the ESR at ambient temperature.
- The ESR in the "Temperature Rise vs. Ripple Current" plots is adjusted to each incremental temperature rise before the power and ripple current is calculated.
- The effects shown herein are based on measured data from a multiple part sample of the parts in question.
- Ripple capability of this device will be factored by thermal resistance (Rth) created by circuit traces (addi affects of all parameters involved, including the specified tolerances applied to capacitance and unspecified variations of ESR, ESL, and leakage resistance.
- The peak voltages generated in the "Temperature Rise vs. Combined Ripple Currents" plot are calculated for each frequency and are not combined with voltages generated at any other harmonics.
- Please consult with the catalog or field applications engineer for maximum capability of the device in specific applications.

All product information and data (collectively, the "Information") are subject to change without notice.

KEMET K-SIM is designed to simulate behavior of components with respect to frequency, ambient temperature, and DC bias levels. The responses shown represent the typical response for each part type. Specific responses may vary, depending on manufacturing variation effects of all parameters involved, including the specified tolerances applied to capacitance and unspecified variations of ESR, ESL, and leakage resistance.

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If you have any questions please contact K-SIM.